



1000V 10A N-Channel Enhancement Mode Power MOSFET

General Description

BXP10N1K is Bridgelux high voltage MOSFET family based on advanced planar DMOS technology. This advanced MOSFET family has optimized on-state resistance, and also provides superior switching performance and higher avalanche energy strength. This device family is suitable for high efficiency switch mode power supplies.

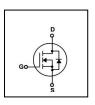
FEATURES

- RDSON≤1.1 Ω @Vgs=10V, Id=5A
- Excellent RDS(ON) and Low Gate Charge

Version: 1.0

- · Fast switching capability
- · Lead free product is acquired

SYMBOL





TO-220F

ASSEMBLY MESSAGE

Product Name	Package	Packaging
BXP10N1KF	TO-220F	Tube

ABSOLUTE MAXIMUM RATINGS (T_C=25°C unless otherwise noted)

Parameter		Symbol	Rating	Unit
		Symbol	BXP10N1KF	Unit
Drain-Source Voltage		V _{DSS}	1000	V
Drain Current	Continuous (T _C = 25°C)		10	А
	Continuous (T _C = 100°C)	- I _D	6.5	А
Drain Current	Pulsed (Note1)	I _{DM}	40	А
Gate-Source Voltage		V _{GSS}	±30	V
Avalanche Energy	Single Pulse (Note2)	E _{AS}	510	mJ
Avalanche Current (Note1)		I _{AR}	10	А
Peak Diode Recovery dv/dt (Note3)		dv/dt	5	V/ns
Power Dissipation (Note	T _C =25°C	Б	31	W
2)	Derate above 25°C	- P _D	0.248	W/°C
Maximum Junction Temperature		TJ	150	°C
Storage Temperature Range		TstG	-55 to 150	°C

Note:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L=10.0mH,V_{DD}=50V, RG=25 Ω , Starting TJ = 25°C
- 3. $I_{SD} \le 10.0 A$, di/dt $\le 300 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting TJ = 25°C



THERMAL CHARACTERISTICS

Doromotor	Symbol	Max.	l lasi4
Parameter		BXP10N1KF	Unit
Thermal Resistance, Junction-to-Case	R _{θJC}	4.03	°C / W
Thermal Resistance, Junction-to-Ambient R _{0JA}		62.5	°C / W

ELECTRICAL CHARACTERISTICS (T_J=25°C,unless otherwise Noted)

Parameter	Symbol	Test Condition	Min.	Тур.	Max.	Unit
OFF CHARACTERISTICS	•					
Drain-Source Breakdown Voltage	BV _{DSS}	VGS=0V, ID=250μA	1000			V
Zero Gate Voltage Drain Current		VDS=1000V, VGS=0V			1	uA
	I _{DSS}	VDS=800V, TC = 125°C			100	uA
Gate-Body Leakage Current, Forward	I _{GSS}	VGS=30V			100	nA
Gate-Body Leakage Current, Reverse		VGS=-30V			-100	nA
Breakdown Voltage Temperature	△BVDSS/	ID = 250 μA		0.55		\//°C
Coefficient	△TJ			0.55		V/℃
ON CHARACTERISTICS	•			•		
Gate Threshold Voltage	V _{GS(TH)}	VDS=VGS, ID=250µA	2.5		4.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	VGS=10V, ID=5A		0.86	1.1	Ω
Forward Transconductance (Note4)	g FS	VDS =15V, ID=5A		7		S
DYNAMIC PARAMETERS				•		
Input Capacitance	C _{ISS}	VDS=25V, VGS=0V, f=1.0MHz		3530		pF
Output Capacitance	Coss			239		pF
Reverse Transfer Capacitance	C _{RSS}	I – I.UIVIDZ		35		pF
SWITCHING PARAMETERS						
Turn-ON Delay Time	t _{D(ON)}	VDD 500V ID 40A		36		ns
Turn-ON Rise Time	t _R	VDD=500V, ID=10A,		38		ns
Turn-OFF Delay Time	t _{D(OFF)}	VGS = 10V ,RG=9.1Ω		43		ns
Turn-OFF Fall-Time	t _F	- (Note4,5)		36		ns
Total Gate Charge(Note5)	Q _G	VDS =500V, VGS =10V,		75		nC
Gate Source Charge	Q _{GS}	ID =10A		15		nC
Gate Drain Charge	Q_{GD}	(Note4,5)		25		nC
SOURCE- DRAIN DIODE RATINGS	AND CHAR	ACTERISTICS	•	•		
Drain-Source Diode Forward Voltage	V _{SD}	IS=10A, VGS=0V			1.5	V
Diode Continuous Forward Current	Is				10	Α
Pulsed Drain-Source Current	I _{SM}				40	Α
Reverse Recovery Time	t _{RR}	VGS = 0 V, ISD = 10A			860	ns
Reverse Recovery Charge	Q _{RR}	di/dt=100 A/µs (Note4,5)			4.5	uC

Note: 4. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%

^{5.} Essentially independent of operating temperature



TYPICAL CHARACTERISTICS

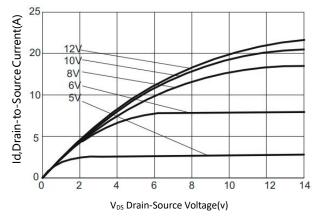


Figure 1. Typical Output Characteristics

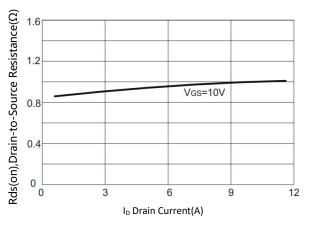


Figure3. On-Resistance versus Drain Current

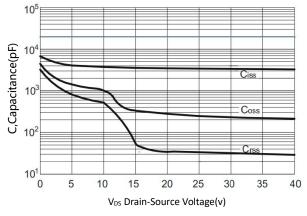


Figure 5. Typical Capacitance versus VDS

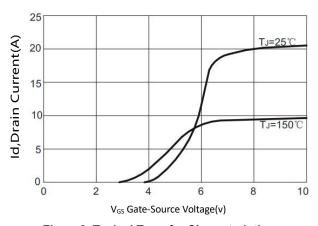


Figure 2. Typical Transfer Characteristics

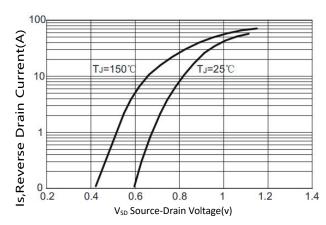


Figure 4. Diode forward voltage versus Current

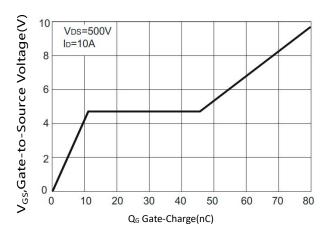


Figure 6. Typical Gate Charge versus V_{GS}



TYPICAL CHARACTERISTICS(Cont.)

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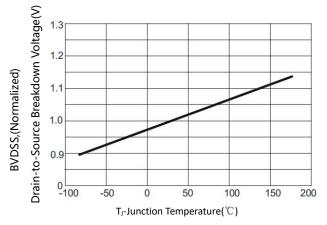


Figure 7. BV_{DSS} Variation with Temperature

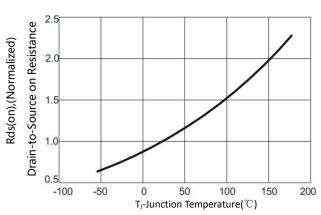


Figure 8. On-Resistance Variation with Temperature

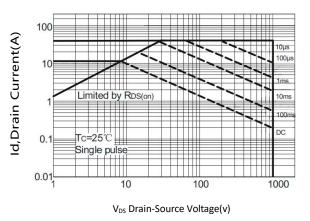


Figure 9. Maximum Safe Operating Area versus Case Temperature

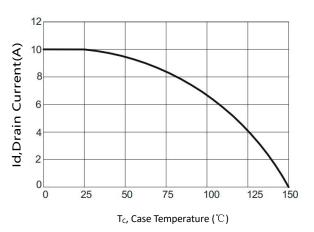
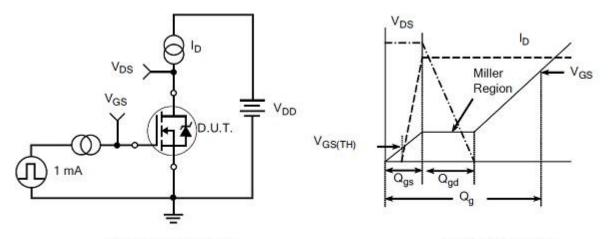


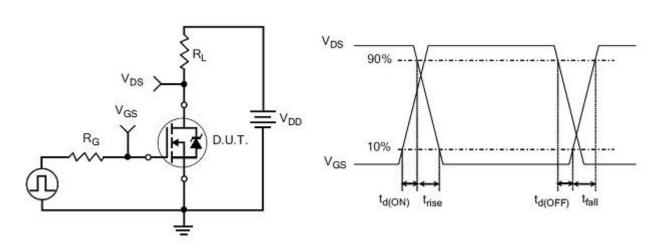
Figure 10. Maximum Continuous Drain Current

TEST CIRCUITS AND WAVEFORMS



Gate Charge Test Circuit

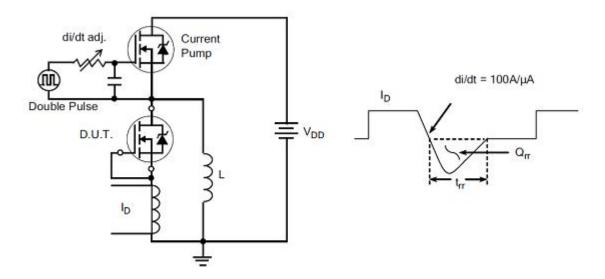
Gate Charge Waveform



Resistive Switching Test Circuit

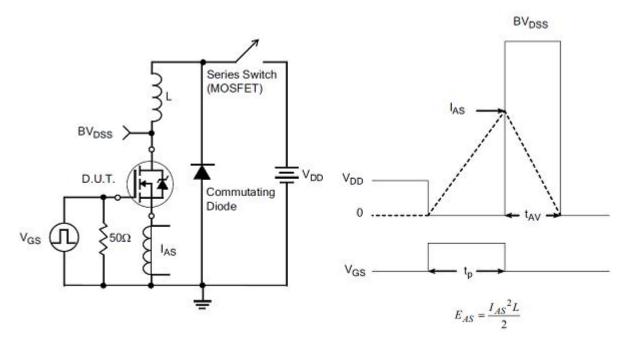
Resistive Switching Waveforms

TEST CIRCUITS AND WAVEFORMS(Cont.)



Diode Reverse Recovery Test Circuit

Diode Reverse Recovery Waveform



Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms





Revision history

Document revision history

Date	Revision	Changes
15-Feb-2022	1.0	First release



Bridgelux WuXi R&D CO.,LTD



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